

Notice of References Cited	Application/Control No. 10/829,283	Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner Stevan A. Resan	Art Unit 1773	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,773,789 B2	08-2004	Murayama et al.	428/141
	B	US-6,120,877 A	09-2000	Deno et al.	428/141
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP-06-052541	02-1994	Japan	Katsumi et al	--
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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